Combining Yield Optimization with Circuit Level Electromagnetic Simulation

M.D. Meehan, P. Draxler and L.C. Henning. "Combining Yield Optimization with Circuit Level Electromagnetic Simulation." 1992 MTT-S International Microwave Symposium Digest 92.3 (1992 Vol. III [MWSYM]): 1469-1472.

A method for first-pass MMIC design success is presented. In this paper we combine the power of statistical design and modeling with that of circuit level electromagnetic simulation in a CAD system, providing the ultimate crystal ball for predicting production success. The performance of the proposed CAD system is verified by comparing simulated vs. actual statistical response characteristics of a 3-stage, 7-11 GHz LNA GaAs MMIC from AT&T Bell Laboratories, Reading, Pennsylvania.

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